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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: James M. Holden, William A. McGahan, Richard A. Yarussi,
Pablo I. Rovira, and Roger R. Lowe-Web
Assignee: Nanometrics Incorporated
Title: Apparatus And Method For The Measurement Of Diffracting Structures
Serial No.: 09/670,000 Filing Date: September 25, 2000
Examiner: Unknown Group Art Unit: Unknown
Docket No.: M-9455 US

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COMMISSIONER FOR PATENTS
Washington, D. C. 20231

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR § 1.97(b)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, the documents listed on the accompanying PTO Form-1449 are called to the attention of the Examiner for the above patent application. Copies of these documents are enclosed.

Citation of these documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on June 15, 2001.

Michael J. Halbert 6-15-01
Attorney for Applicants Date of Signature

Respectfully submitted,

Michael J. Halbert

Michael J. Halbert
Attorney for Applicants
Reg. No. 40,633

LAW OFFICES OF
SKJERVEN MORRILL
MacPHERSON LLP

25 METRO DRIVE
SUITE 700
SAN JOSE, CA 95110
(408) 453-9200
FAX (408) 453-7979